


<b>Search Notes</b> 	<b>Application No.</b>	<b>Applicant(s)</b>	
	09/772,493	DUEMLER, DAVID W.	
	<b>Examiner</b>	<b>Art Unit</b>	
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SEARCHED			
Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
IEEE Xplore	4/1/2005	LVN